Wednesday, November 22, 2023

PHOTONICS spectra®

WEBINARS

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High-Resolution Measurement of Film Thickness and Refractive Index for Silicon Photonics and Planar Waveguide Applications

Wednesday, December 6, 2023 1:00 PM - 2:00 PM EST

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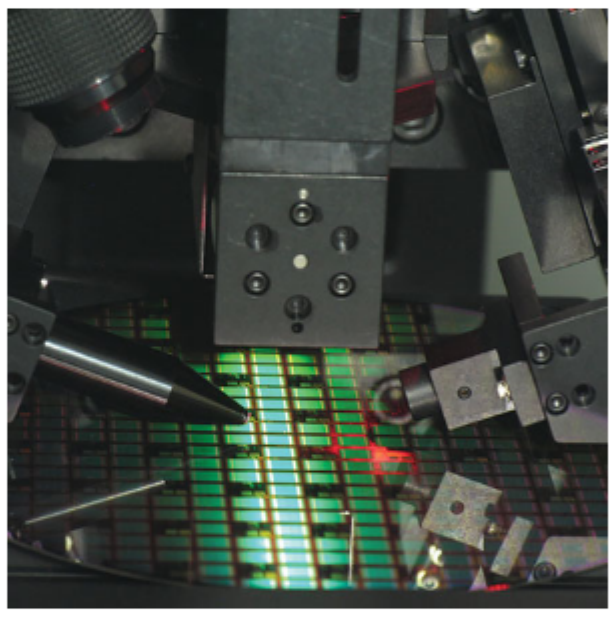
Presented by

BRUKER

This webinar provides an overview of advanced measurement technologies tailored to meet the high-resolution demands of silicon photonics and planar waveguide applications. Lawrence Rooney of Bruker shares about state-of-the-art film thickness and refractive index measurement techniques, including multi-angle spectroscopic reflectometry and ellipsometry, and discusses their respective advantages, limitations, and suitability for different types of multi-layer photonic structures. He also highlights the critical importance of high-resolution film thickness and refractive index measurement techniques in the advancement of silicon photonics and planar waveguide applications. Presented by Bruker.



Upcoming Webinars

- The Etendue Mystery Revealed, 11/28/2023 10:00:00 AM EST
- Design and Optimization of Optical Waveguides, 11/30/2023 2:00:00 PM EST
- Quantum Efficiency Measurements: Fundamentals for Solar Cell Research, Part 1, 12/5/2023 1:00:00 PM EST

Archived Webinars

- Optimization of Surface Enhanced Spatially Offset Raman Spectroscopy for Applications in Pre-Clinical Cancer Imaging
- Next-Generation Instrumentation for Optical Control and Characterization
- Mastering Diffraction Gratings: Selection and Integration Techniques for Analytical Instrumentation

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